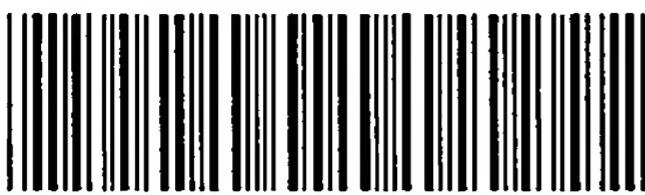


## **Search Notes**



**Application/Control No.**

10/646,651

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Examiner

Hai C. Pham

**Applicant(s)/Patent under  
Reexamination**

ZWADLO ET AL.

## **Art Unit**

2861

**SEARCHED**

## **INTERFERENCE SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**